





Page 1 of 30

Repor

EMC TEST REPORT

Product	e la
Trade mark	:
Model/Type reference	:
Serial Number	:
Ratings	:
Report Number	:
Date of Issue	1
Regulations	- (F)

- **Circular Connector**
- N/A
 - DP29, DP11, DP13, DP17, DP21
- N/A
 - 220-240V~50Hz
 - EED32Q818749
 - Dec. 02, 2024
 - See below

Test Standards	Results
EN IEC 61000-6-2:2019	PASS
EN IEC 61000-6-4:2019	PASS

Prepared for:

GuangDong WanLian Technology Co., LTD Room 106, No.6 Xixing Street, Chang 'an Town, **Dongguan City, Guangdong Province**

Prepared by:

Centre Testing International Group Co., Ltd. Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China TEL: +86-755-3368 3668 FAX: +86-755-3368 3385

Compiled by: Approved by: CTU BUILT CTU CTU CTU CTU CTU CTU CTU CTU CTU CT		Will Gan Aaron Ma Aaron Ma	 Reviewed by: Date of Issue:		Alcm - Chen Dec. 02, 2024 Check No.: 6306181124	
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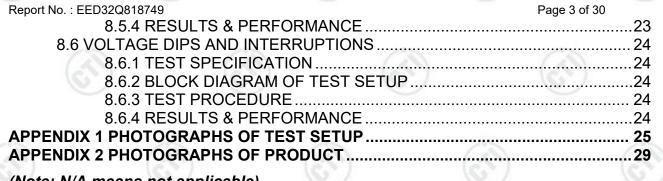




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1. GENERAL INFORMATION

Applicant:	GuangDong WanLian Technology Co., LTD
	Room 106, No.6 Xixing Street, Chang 'an Town, Dongguan
	City, Guangdong Province
Manufacturer:	GuangDong WanLian Technology Co., LTD
	Room 106, No.6 Xixing Street, Chang 'an Town, Dongguan City, Guangdong Province
EMC Directive:	2014/30/EU
Product:	Circular Connector
Trade mark:	N/A
Model/Type reference:	DP29, DP11, DP13, DP17, DP21
Serial Number:	N/A
Report Number:	EED32Q818749
State of Sample(s):	Normal
Sample Received Date:	Nov. 18, 2024
Sample tested Date:	Nov. 18, 2024 to Nov. 27, 2024

Company Name and Address shown on Report, the sample(s) and sample Information was/ were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified.

2. TEST SUMMARY

The Product has been tested according to the following specifications:

EMISSION						
Standard Test Item T						
EN IEC 61000-6-4 Conducted disturbance						
EN IEC 61000-6-4	Radiated disturbance	Yes				

IMMUNITY (EN IEC 61000-6-2)						
Standard	Test Item	Test				
IEC 61000-4-2	Electrostatic discharge (ESD)					
IEC 61000-4-3	Radio-frequency electromagnetic field Immunity					
IEC 61000-4-4	Electrical fast transients (EFT)					
IEC 61000-4-5	Surges	Yes				
IEC 61000-4-6	Radio-frequency continuous conducted Immunity	Yes				
IEC 61000-4-8	I-8 Power-frequency magnetic fields Immunity					
IEC 61000-4-11	Voltage dips and interruptions	Yes				

1. The Product doesn't contain any device susceptible to magnetic fields.





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TEST UNCERTAINTY 3.

Where relevant, the following test uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Test item	Value (dB)	
Conducted emissions	3.1	
Radiated emissions (30MHz to 1GHz)	4.9	

PRODUCT INFORMATION AND TEST SETUP 4.

4.1 PRODUCT INFORMATION

Ratings:

Model difference:

108MHz:

220-240V~50Hz

All models are identical except for the model name, appearance and color. The test model is DP29, the test results are applicable to the others.

- The highest frequency of \boxtimes less than or equal 108 MHz, the measurement shall only be the internal sources of made up to 1 GHz. the EUT is less than
 - between 108 MHz and 500 MHz, the measurement shall only be made up to 2 GHz.
 - between 500 MHz and 1 GHz, the measurement shall only be made up to 5 GHz.
 - above 1 GHz, the measurement shall be made up to 6GHz.

4.2 TEST SETUP CONFIGURATION

See test photographs attached in Appendix 1 for the actual connections between Product and support equipment.

4.3 TEST MODE DESCRIPTION

Test Mode	Test Status				
1	Normal mode: The product can operate normally.				

4.4 SUPPORT EQUIPMENT

No.	Device Type	Brand	Series No.	Model	Data Cable	Power Cord

Notes:

1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.

2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

FACILITIES AND ACCREDITATIONS 5.

5.1 TEST FACILITY

All test facilities used to collect the test data are located at Hongwei Industrial Zone, Bao'an 70 District, Shenzhen, Guangdong, China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4, CISPR 16-1-1 and other equivalent





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Report No. : EED32Q818749 standards.

5.2 TEST EQUIPMENT LIST

Instrumentation: The following list contains equipments used at CTI for testing. The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

Equipment used during the tests:

Shielding Room No. 3_Hongwei-Conducted emissions								
Equipment	Manufacturer	Model	Series No.	Due Date				
Receiver	R&S	ESCI	100435	04/17/2025				
LISN	R&S	ENV216	100098	09/18/2025				
Software-EZ	Farad Technology	- 6	EMC-CON 3A1.1	57) -				

3M Semi-anechoic Chamber (1)_Hongwei-Radiated emissions								
Equipment	Manufacturer	Model	Series No.	Due Date				
3M Chamber & Accessory Equipment	ETS-LINDGREN	FACT-3	3510	05/19/2025				
Receiver	R&S	ESCI	100009	04/17/2025				
TRILOG Broadband Antenna	Schwarzbeck	VULB9163	9163-484	04/29/2025				
Multi device Controller	ETS-LINDGREN	2090	00024675					
Software-EZ	Farad Technology	- (Ver.FA-03A2 RE+	- ()				

Shielding Room No. 1_Hongwei-Electrostatic discharge (ESD)							
Equipment	Manufacturer	Model	Series No.	Due Date			
ESD Simulator	TESEQ	NSG437	1182	06/02/2025			

3M Semi-anechoic Chamber (1)_Hongwei-Continuous RF electromagnetic radiated field disturbances

disturbances						
Equipment	Manufacturer	Model	Series No.	Due Date		
3M Chamber & Accessory Equipment	ETS-LINDGREN	FACT-3	3510	05/19/2025		
Signal Generator	R&S	SMB 100B	103084	05/12/2025		
Horn Antenna	Schwarzbeck	STLP 9149	0776	06/05/2026		
Stacked double LogPer. Antenna	Schwarzbeck	STLP9128	9128ES-110	03/21/2026		
Directional coupler	BONN	BONN BDC 1060-40/500 2128343-04		11/10/2025		
RF switch	R&S	R&S OSP220		- ()		
Power Amplifier	BONN	BLMA 1060-100	2113427	07/21/2025		
Power Amplifier	R&S	BBA 150-BC500	104743	05/30/2025		
Power Probe	R&S	NRP6A	103343	06/24/2025		
Power Probe	R&S	NRP6A	103342	06/24/2025		
Software-EMC-32	R&S	- (2)	V10.60.20-Y267 _FU	- (N		

Shielding Room No. 1_Hongwei-Electrical fast transients/burst (EFT/B)								
Equipment	Manufacturer	Model	Series No.	Due Date				
Electric fast transient pulse group simulator	3ctest	EFT 600T	ES027000923002	04/27/2025				
	5	6		0				









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Shielding Room No. 2_Hongwei-Surges						
Equipment	Manufacturer	Model	Series No.	Due Date		
Compact Generator	EM TEST	UCS500M/6B	V0603101093	03/07/2025		
Software-ISMIEC	EM-TEST	-	4.07			

Shielding Room No. 2_Hongwei-Continuous induced RF disturbances							
Equipment	Manufacturer	Model	Series No.	Due Date			
Conducted immunity test system	TESEQ	NSG 4070C-80	59089	06/25/2025			
CDN	TESEQ	CDN M516AS	59088	09/01/2025			
Attenuator	BIRD	75-A-MFN-06	0543	06/24/2025			
Software-NSG 4070 Control Pgram	TESEQ	- (2)	1.4.0	- 62			

Shield	ing Room No. 2_Ho	ngwei-Voltage dips a	nd interruptions	
Equipment	Manufacturer	Model	Series No.	Due Date
Power supply	california instrument	15003ix-CTS-400- 413-EOS3-LF	1726A00002	05/30/2025
Electronic switch	california instrument	EOS3-230	1726A00001	09/18/2025
Software-AC Source CIGuiSII	California instrument		3.2.0	

5.3 LABORATORY ACCREDITATIONS AND LISTINGS

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable under the ISO/IEC 17025 to international or national standards. Equipment has been calibrated by accredited calibration laboratories.







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6. CONDUCTED DISTURBANCE

6.1 LIMITS

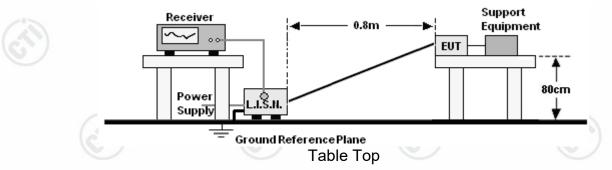
requency range	Lim dB(j	
(MHz)	Quasi-peak	Average
0,15 to 0,50	79	66
0,50 to 30	73	60

NOTE: 1. The lower limit shall apply at the transition frequencies.

2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 to 0.50 MHz.

6.2 BLOCK DIAGRAM OF TEST SETUP

For AC mains power port:



6.3 TEST PROCEDURE

For AC mains power port: (Table Top):

a. The Product was placed on a nonconductive table 0.8 m above the horizontal ground reference plane, and 0.4 m from the vertical ground reference plane, and connected to the main through Line Impedance Stability Network (L.I.S.N).

b. The RBW of the receiver was set at 9 kHz in 150 kHz ~ 30MHz with Peak and AVG detector in Max Hold mode. Run the receiver's pre-scan to record the maximum disturbance generated from Product in all power lines in the full band.

c. For each frequency whose maximum record was higher or close to limit, measure its QP and AVG values and record.

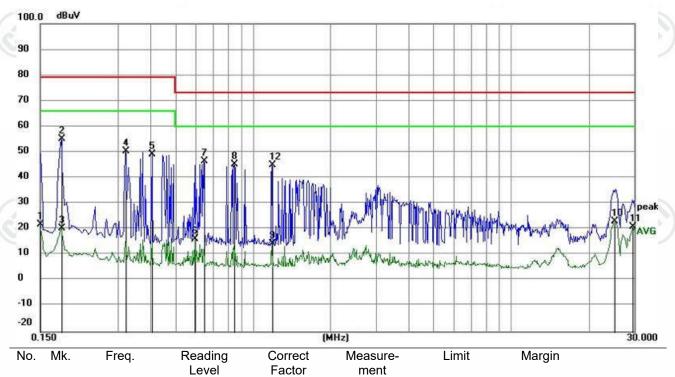




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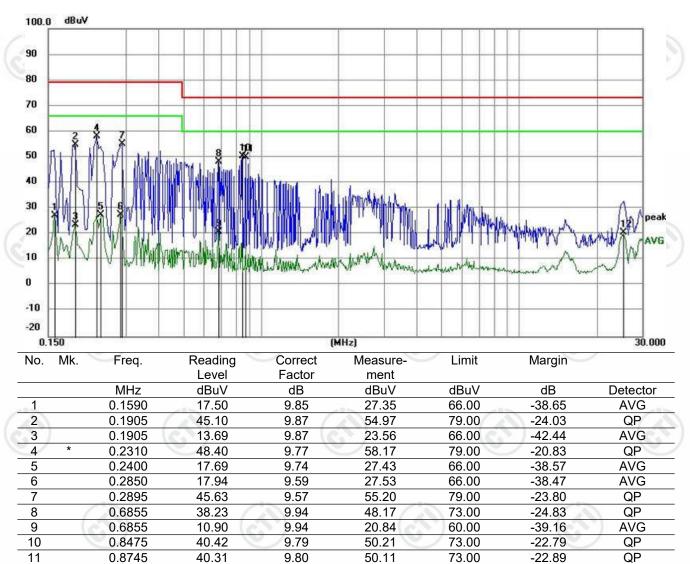
Report No. : EED32Q818749

6.4 GRAPHS AND DA	ATA				
Product	:	Circular Connector	-05		10-
Model/Type reference	:	DP29			
Power	:	AC 230V/50Hz	Temperature	:	23 ℃
Mode	:	1	Humidity	:	53%R.H.
Phase	:	L1	Press	:	101KPa



		Level	Factor	ment			
	MHz	dBuV	dB	dBuV	dBuV	dB	Detector
1	0.1500	12.08	9.84	21.92	66.00	-44.08	AVG
2 *	0.1815	45.16	9.86	55.02	79.00	-23.98	QP
3	0.1815	10.56	9.86	20.42	66.00	-45.58	AVG
4	0.3209	40.76	9.59	50.35	79.00	-28.65	QP
5	0.4065	39.30	9.79	49.09	79.00	-29.91	QP
6	0.5955	6.42	9.60	16.02	60.00	-43.98	AVG
7	0.6450	36.64	9.78	46.42	73.00	-26.58	QP
8	0.8475	35.33	9.79	45.12	73.00	-27.88	QP
9	1.1895	4.67	9.74	14.41	60.00	-45.59	AVG
10	25.0620	13.13	9.91	23.04	60.00	-36.96	AVG
11	29.5800	11.01	9.80	20.81	60.00	-39.19	AVG
12	1.1895	35.14	9.74	44.88	73.00	-28.12	QP
10							0

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Product	:	Circular Connector			
Model/Type reference	:	DP29			
Power	:	AC 230V/50Hz	Temperature	:	23 ℃
Mode	:	1	Humidity	:	53%R.H.
Phase	:	N	Press	:	101KPa



12 Note:

1. Margin=Measurement-Limit.

25.4265

2. Measurement=Reading Level+Correct Factor.

10.83

9.90

20.73

60.00





-39.27

AVG



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7. RADIATED DISTURBANCE (RE)

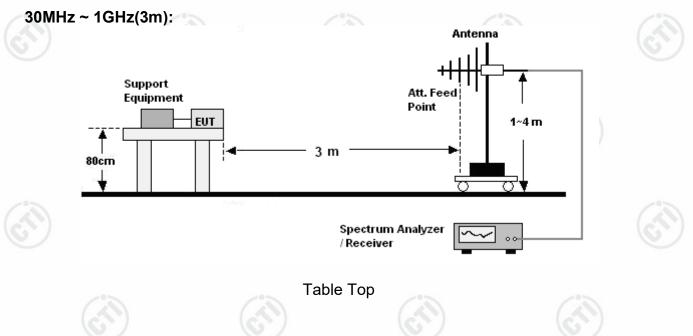
7.1 LIMITS

Requirements for radiated emissions at frequencies up to 1 GHz

30MHz ~ 1GHz(3m):

(\mathcal{S})	Frequency (MHz)	Quasi-peak limits at 3m dB(µV/m)
	30-230	50
	230-1000	57
	(F) (F	(4) (4) (4)

7.2 BLOCK DIAGRAM OF TEST SETUP



7.3 TEST PROCEDURE

30MHz ~ 1GHz(Table Top):

a. The Product was placed on the non-conductive turntable 0.8 m above the ground at a chamber.

b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 120 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.

c. For each frequency whose maximum record was higher or close to limit, measure its QP value: vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.

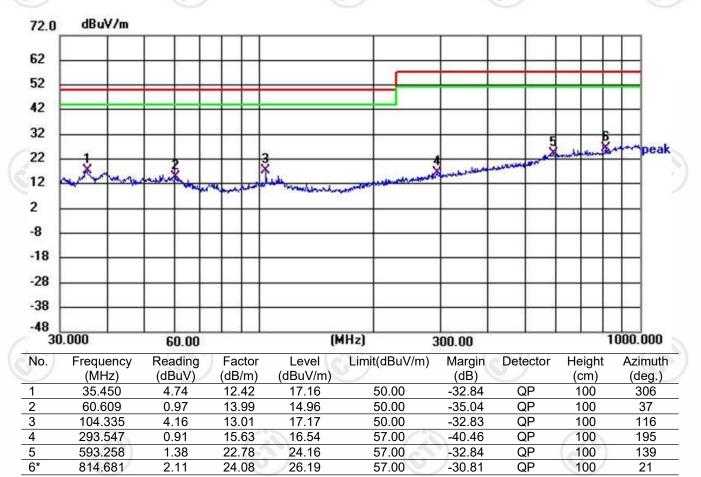
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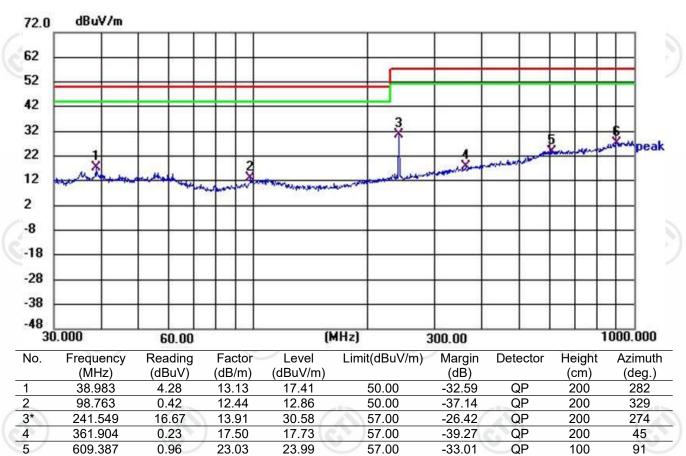
7.4 GRAPHS AND DATA

Product	:	Circular Connector				
Model/Type reference	:	DP29				
Power	:	AC 230V/50Hz	Temperature		22 ℃	
Mode	1	1	Humidity		54%R.H.	
Polarization	Ŀ.	Vertical	Press	57 1	101KPa	





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Product	:	Circular Connector			
Model/Type reference	:	DP29			
Power	:	AC 230V/50Hz	Temperature	:	22 ℃
Mode	:	1	Humidity	:	54%R.H.
Polarization	:	Horizontal	Press	:	101KPa



Note:

6

1. Margin=Measurement-Limit.

905.212

2. Measurement=Reading Level+Correct Factor.

1.50

25.70

27.20

57.00

-29.80

QP

100

274





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8. IMMUNITY TEST

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	General Performance Criteria					
Product Standard	EN IEC 61000-6-2:2019					
CRITERION A	The equipment shall continue to operate as intended without operator intervention. No degradation of performance, loss of function or change of operating state is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance leve may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.					
	During the application of the disturbance, degradation of performance is allowed. However, no unintended change of actual operating state or stored data is allowed to persist after the test.					
CRITERION B	After the test, the equipment shall continue to operate as intended without operator intervention; no degradation of performance or loss of function is allowed, below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.					
	If the minimum performance level (or the permissible performance loss), or recovery time, is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the use may reasonably expect from the equipment if used as intended.					
	Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. A reboot or re-start operation is allowed.					
	Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.					



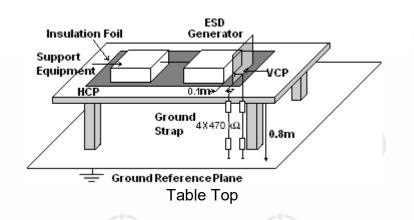






CTI华测检测 Page 15 of 30 Report No. : EED32Q818749 8.1 ELECTROSTATIC DISCHARGE (ESD) 8.1.1 TEST SPECIFICATION EN IEC 61000-6-2 & IEC 61000-4-2 **Basic Standard Test Port** Enclosure port **Discharge Impedance** 330 ohm / 150 pF **Discharge Mode** : Single Discharge **Discharge Period** one second between each discharge

8.1.2 BLOCK DIAGRAM OF TEST SETUP



8.1.3 TEST PROCEDURE

a. Electrostatic discharges were applied only to those points and surfaces of the Product that are accessible to users during normal operation.

b. The test was performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.

c. The time interval between two successive single discharges was at least 1 second.

d. The ESD generator was held perpendicularly to the surface to which the discharge was applied and the return cable was at least 0.2 meters from the Product.

e. Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.

f. Air discharges were applied with the round discharge tip of the discharge electrode approaching the Product as fast as possible (without causing mechanical damage) to touch the Product. After each discharge, the ESD generator was removed from the Product and re-triggered for a new single discharge. The test was repeated until all discharges were complete.

g. At least ten single discharges (in the most sensitive polarity) were applied to the Horizontal Coupling Plane at points on each side of the Product. The ESD generator was positioned vertically at a distance of 0.1 meters from the Product with the discharge electrode touching the HCP.

h. At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane in sufficiently different positions that the four

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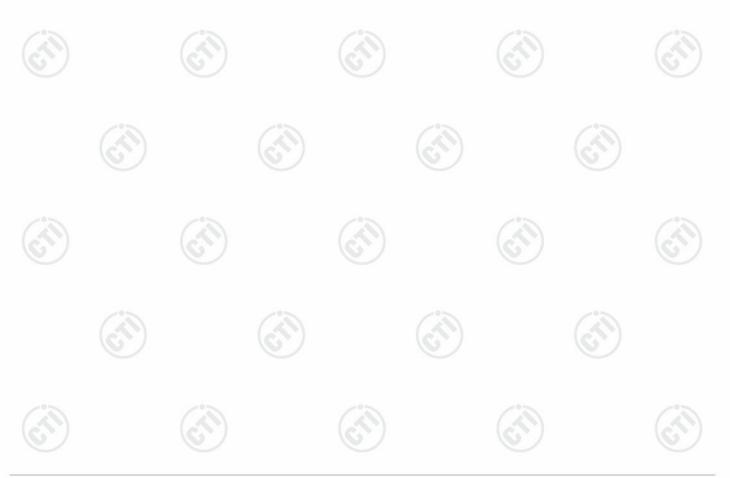
faces of the Product were completely illuminated. The VCP (dimensions 0.5m x 0.5m) was placed vertically to and 0.1 meters from the Product.

8.1.4 RESULTS & PERFORMANCE

Product	:	Circular Connector				
Model/Type reference	:	DP29				
Power	100	AC 230V/50Hz	Temperature	100	:	24°C
Mode	2	1	Humidity	(2)	:	53%R.H.
Press		101kPa		6	1	0

Discharge Method	Discharge Position	Voltage(±kV)	Min. No. of Discharge per polarity(Each Point)	Performance Criterion	Test Result
Contact Discharge	Conductive Surfaces	4	10	В	А
Contact Discharge	Indirect Discharge HCP	4	10	В	A
Contact Discharge	Indirect Discharge VCP	4	10	В	A
Air Discharge	Apertures and Insulating Surfaces	8	10	В	A

Note: No observable degradation in performance.



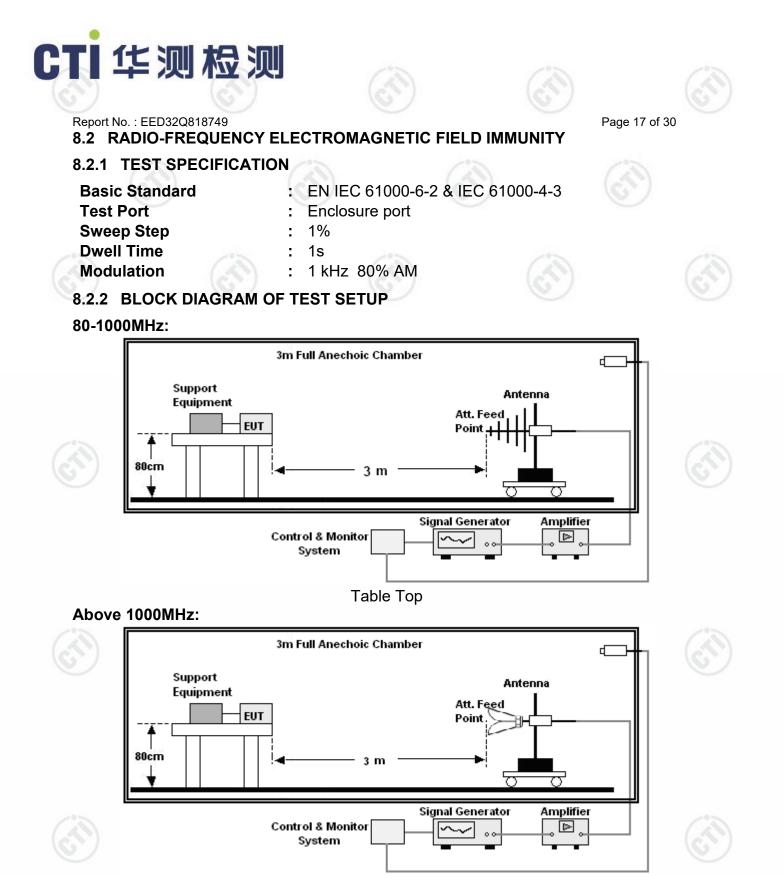


Table Top

8.2.3 TEST PROCEDURE

a. The testing was performed in a fully-anechoic chamber. The transmit antenna was located at a distance of 3 meters from the Product.

b. The frequency range is swept from 80MHz to 1000MHz, 1400MHz to 6000MHz with the signal 80% amplitude modulated with a 1 kHz sine wave. The rate of sweep did not exceed



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1.5x 10⁻³ decade/s. Where the frequency range is swept incrementally, the step size was 1%.

c. The test was performed with the Product exposed to both vertically and horizontally polarized fields on each of the four sides.

8.2.4 RESULTS & PERFORMANCE

1	Circular Connector			
S):	DP29		0	
9:	AC 230V/50Hz	Temperature		23°C
:	1	Humidity	:	52%R.H.
:	101kPakPa			•
		: DP29 : AC 230V/50Hz : ①	: DP29 : AC 230V/50Hz Temperature : 1 Humidity	: DP29 : AC 230V/50Hz Temperature : : ① Humidity :

Frequency(MHz)	Position	Position Field Strength(V/m)		Test Result		
80 - 1000	Front,Right,Back,Left	10	Α	A		
1400-6000	Front,Right,Back,Left	3	A	A		

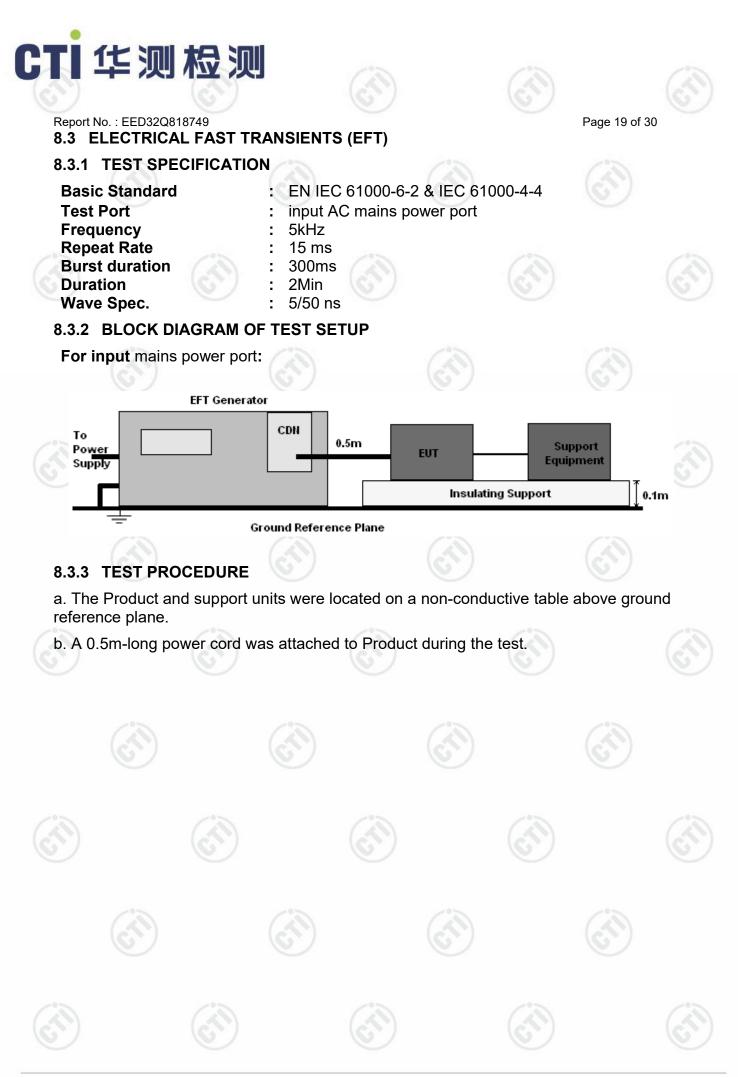
















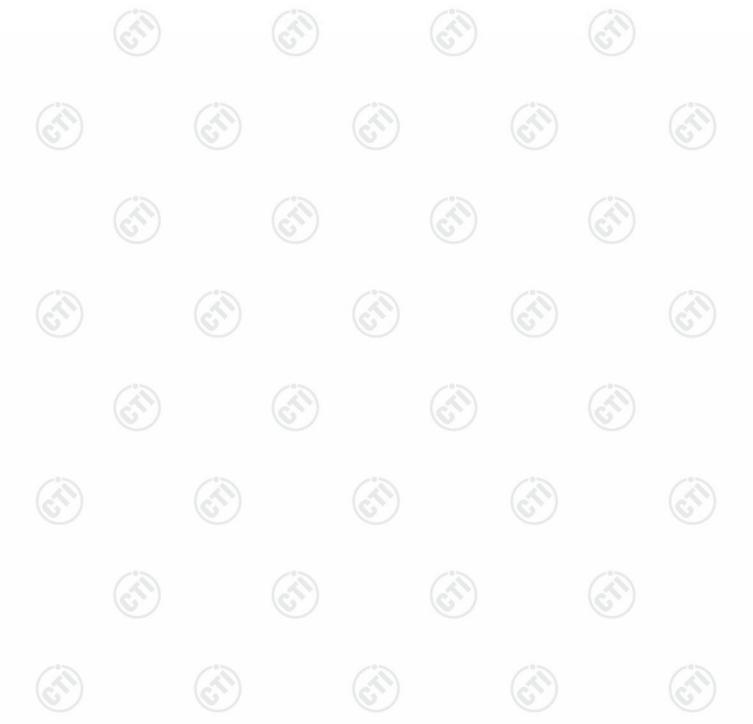
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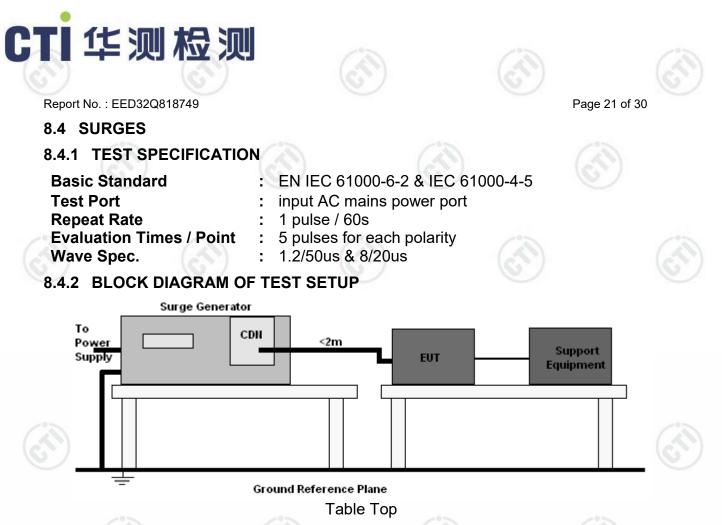
Report No. : EED32Q818749

8.3.4 RESULTS & PERFORMANCE

Product	:	Circular Connector	12		10
Model/Type reference	:	DP29	(\sim)		$(\sim \sim)$
Power	:	AC 230V/50Hz	Temperature	:	23 ℃
Mode	:	1	Humidity	:	56%R.H.
Press	:	101kPa	÷		

Coupling	Voltage(kV)	Polarity	Performance Criterion	Test Result
AC mains power port	2	<u>±</u>	В	A





8.4.3 TEST PROCEDURE

a. The surge is to be applied to the Product power supply terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines, and to provide sufficient decoupling impedance to the surge wave.

b. The power cord between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter). Interconnection line between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter).







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8.4.4 RESULTS & PERFORMANCE

Product	:	Circular Connector	13		1°2
Model/Type reference	:	DP29			(2)
Power	:	AC 230V/50Hz	Temperature	:	23 ℃
Mode	:	1)	Humidity	:	50%R.H.
Press	:	101kPa		•	

Coupling	Voltage(kV)	Polarity	Phase Angle	Performance Criterion	Test Result
AC mains power port	1	±	0°,90°,180°,270°	В	А



CTI 华测极》 Report No.: EED32Q818749		Page 23 of 3	
	CONTINUOUS CONDUCTE	-	0
8.5.1 TEST SPECIFICAT	ION		
Basic Standard Test Port Sweep Step Dwell Time Modulation	 EN IEC 61000-6-2 & IE input AC mains power p 1% 1s 1 kHz 80% AM 		
8.5.2 BLOCK DIAGRAM For input AC mains pow	ver port :		
Control System	Amplifier To Power Supply Attenuator /	Support Equipment	

-Ground Reference Plane

CDN

Insulating Support

0.1m

Attenuator

8.5.3 TEST PROCEDURE

For input AC mains power port:

a. The product and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.

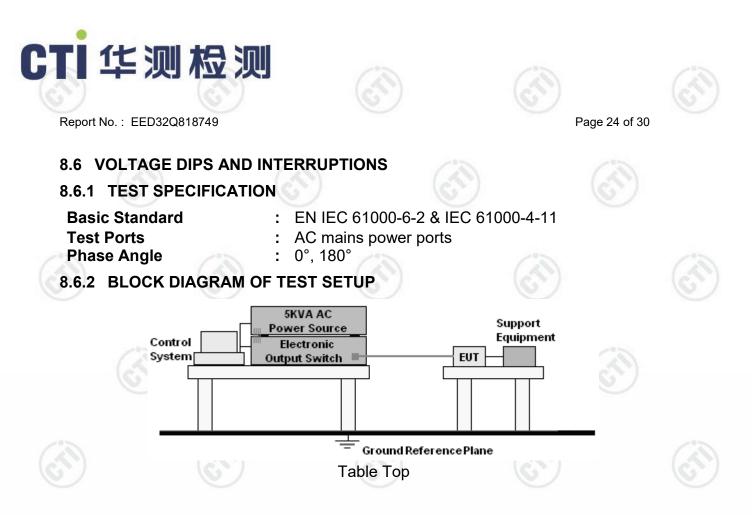
b. The frequency range is swept from 150 kHz to 80MHz, with the signal 80% amplitude modulated with a 1 kHz sine wave. The rate of sweep did not exceed 1.5×10^{-3} decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.

c. The dwell time at each frequency shall be not less than the time necessary for the product to be able to respond.

8.5.4 RESULTS & PERFORMANCE

Product	:	Circular Connector				
Model/Type reference	1:	DP29		(Λ)		
Power	:	AC 230V/50Hz	Temperature		:	23 °C
Mode	:	1)	Humidity		:	50%R.H.
Press	:	101kPa				(1)

Inject Line	Frequency(MHz)	Voltage Level(V r.m.s.)	Performance Criterion	Test Result
AC mains power port	0.15 to 80	10	А	A



8.6.3 TEST PROCEDURE

a. The Product and support units were located on a non-conductive table above ground floor.

- b. Set the parameter of tests and then perform the test software of test simulator.
- c. Conditions changes to occur at 0 degree crossover point of the voltage waveform.

Product	1:	Circular Connector				
Model/Type reference	:	DP29		U		
Power	:	AC 230V/50Hz	Temperature		:	23 ℃
Mode	:	1	Humidity		:	50%R.H.
Press	:	101kPa				

8.6.4 RESULTS & PERFORMANCE

Voltage Dips:

Test Level% UT	Reduction(%)	Number of cycles 50Hz 50Hz	Number of cycles 60Hz 60Hz	Performance Criterion	Test Result
0	100	1 (2	N/A	В	A
40	60	10	N/A	С	A
70	30	25	N/A	С	A

Voltage Interruptions:

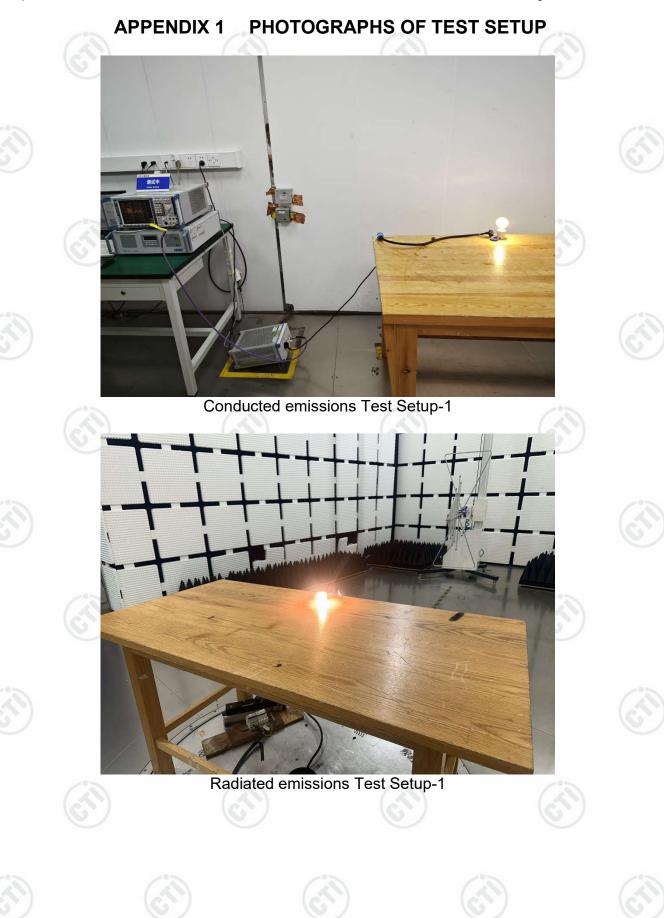
Test Level% Reduction(%) UT		Number of cycles 50Hz 50Hz	Number of cycles 60Hz 60Hz	Performance Criterion	Test Result
0	100	250	N/A	С	B*

Remark*: The product stopped working during the test, but it can recover by itself after testing.



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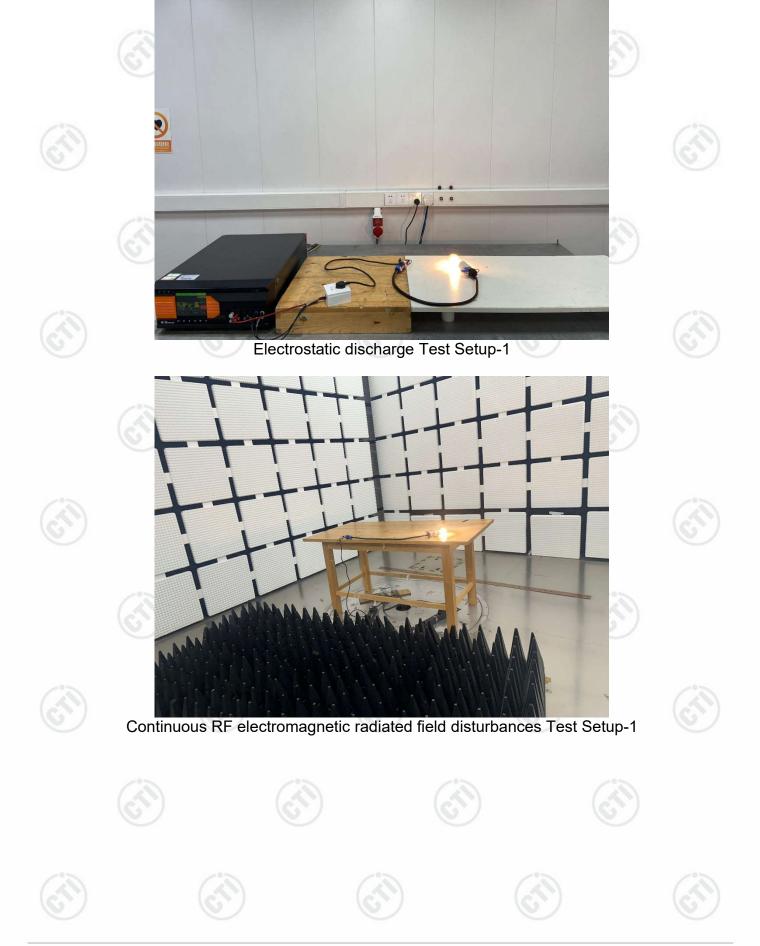


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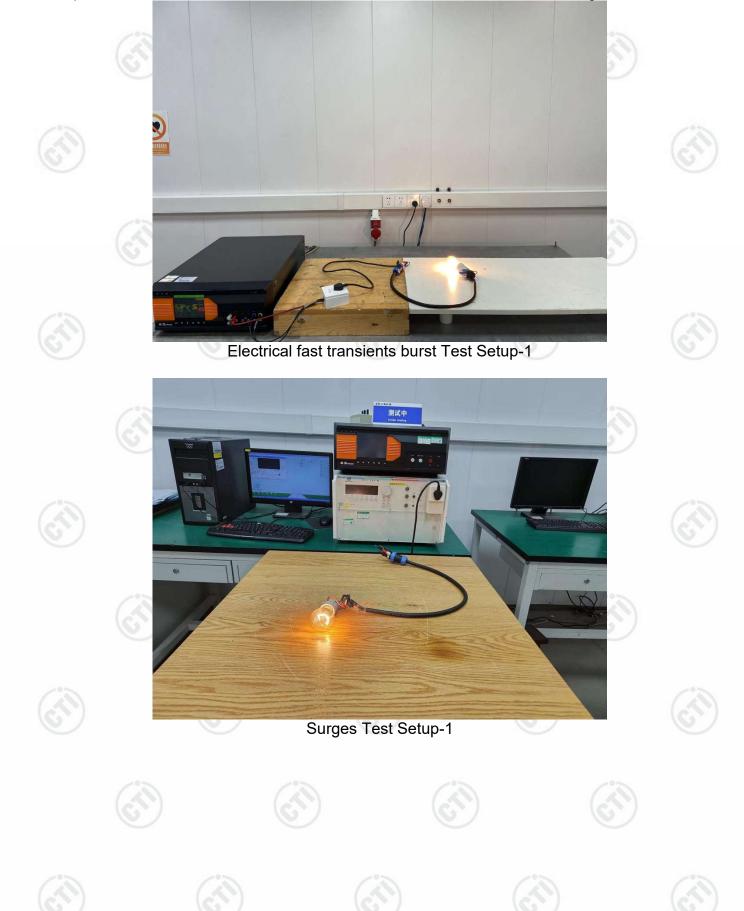


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Continuous induced RF disturbances Test Setup-1



Voltage dips and interruptions Test Setup-1





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View Of Product-01





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